

Study of Geiger Avalanche Photo Diode applications to pixel tracking detectors



Barcelona

Main Goal

The use of std CMOS tech. APD's in Geiger mode (that is reverse-biased above breakdown) as sensors with integrated logic, for direct particle detection in pixel tracking detectors

Tracking applications require:

- High Fill Factor (>90%)
- High Efficiency

Collateral (std) Application: Single photon detection for (astro-)particle physics, medical devices, etc..

Pros:

- Ionization production of Avalanche starting carrier → Part. Detect.
- Std CMOS tech mature and supported for custom design
 - Integrated and Active Quenching (& active circuits) to minimize avalanche charge, cross-talk and after-pulsing
 - Gate mode (bunch crossing)
- Monolithic integration → System on chip
- Moderate (low) cost
 - Very Low material budget: Depletion region ~1 μm ~80 e/h pairs!
 - Very high SNR (but only binary detectors)

Cons:

- Fill factor limited to wells width
- Dark count rate (High Geiger eff. even at low excess bias V)
- Cross-talk (to handel lowering the excess bias V)
- After-pulsing (trapped carriers & delayed release; worse w/ cooling)

Approach

Device simulations

Edge breakdown / termination
Charge collection: sensitive area (?)
Quenching and recharge methods

Test

I-V curves
Signal: LASER, particles
Dark count rate, After pulsing...
Crosstalk

Tune simulations

Design and proto

Basic structures
Pixel electronics
Matrices with digital readout

Choose tech. and structure

Deep SubMicron tech. proto

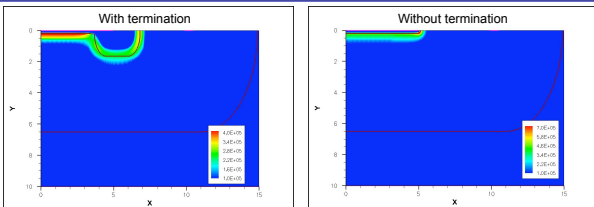
• Test: Integrated and Active Quenching

Test Setup

- 3D Traslation system: Newport ESP300
 - Resolution 0.1 μm
 - Absolute accuracy 5μm
- Black Box above isolation station
- Keithley 2612 power supply
- Oscilloscope: TDS3032 and TDS7154B
- Light source:
 - LED λ = 465nm, FWHM=850ps
 - Laser λ = 631nm, FWHM=50ps

Device simulation at CNM-IMB → Sentaurus T-CAD soft :

- AMS HV 350nm CMOS tech ⇒ PTUB termination allows breakdown at ~15V

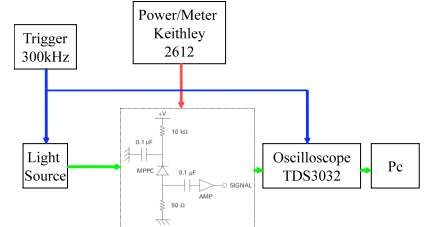
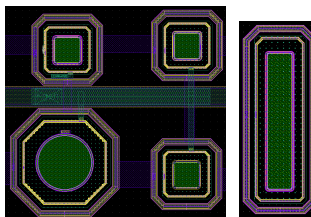
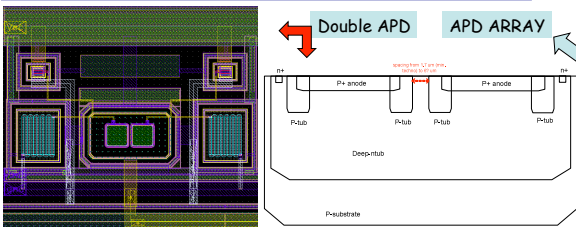


Proto's in HV CMOS:

- Test: tech layers, structure & shape.
- Layers for termination:
 - Deep p tub
 - Deep p tub and shallow n tub
 - No termination.
- Shape:
 - Classical circular shape (20 μm radius).
 - Square shape (20 μm side with rounded corners, curvature is 10 % of square side).
 - Rectangular pixels (20 μm x 100 μm, curvature is 10 % of 20 μm side).
- Rectangular pixel is optimized for ILC forward tracking

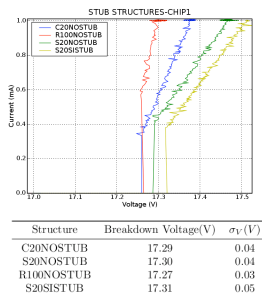
Proto's in HV CMOS:

- APD's w/ output buffer: To minimize output load (parasitic) capacitance which impacts performance: time response, after-pulsing, dark count, x-talk
- Double APD and APD array:
 - Fill factor ↑; pixel separation minimal (Min. DNTUB distance α(10 μm)).
 - Different pixels in the same DNTUB (common cathode).
 - Minimal separation is min. ptub distance (1.7 μm).
 - Problem sharing DNTUB: Electrons diffusing in the deep ntub could reach any pixel: electrical "crosstalk"...

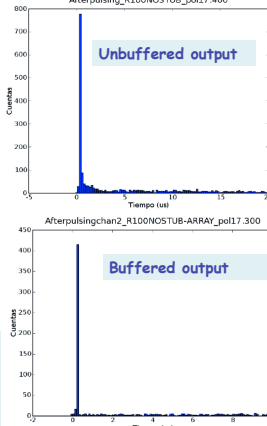


Measurement Results

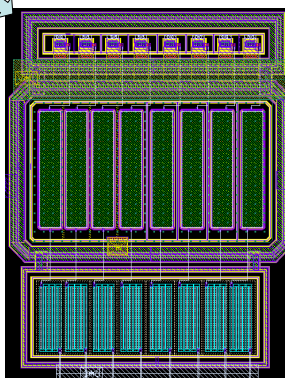
Termination works: Planar breakdown, close to simulations, stable



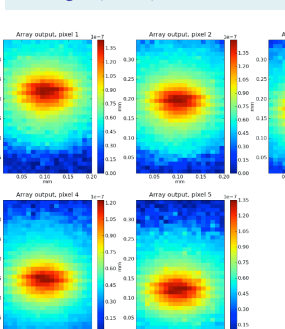
APD array pixel after-pulsing: Check the effect of a buffered output on after-pulsing



Preliminary measurements show that the unbuffered output channel shows signals with more counts after light signal. With buffered output the after-pulsing is almost suppressed



Laser light (631nm) scan on APD array



Key Measurements:

- Response to light and part.
- I-V characteristics
- Gain vs polarization
- Time resolution
- Dark current
- After-pulsing
- Cross-talk

